

**Search Notes**

Application/Control No.

10/784,678

Examiner

Stephen J. Stein

Applicant(s)/Patent under  
Reexamination

FUKAYA ET AL.

Art Unit

1775

**SEARCHED**

Class	Subclass	Date	Examiner
428	469	2/3/2006	SJS
428	702	2/3/2006	SJS
<i>to date 07/06 ms</i>			

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Search	2/3/2006	SJS
West Search (JPO/EPO/Derwent/USPAT) (PGPUBS)	2/2/2006	SJS